

# A 5-DC-parameter MOSFET model for circuit simulation in QucsStudio and SPECTRE

Deni G. Alves Neto<sup>1</sup>, Cristina M. Adornes<sup>1</sup>, Gabriel Maranhão<sup>1</sup>, Mohamed K. Bouchoucha<sup>2,3</sup>, Manuel J. Barragan<sup>3</sup>, Andreia Cathelin<sup>2</sup>, Marcio C. Schneider<sup>1</sup>, Sylvain Bourdel<sup>3</sup> and Carlos Galup-Montoro<sup>1</sup>

<sup>1</sup>Federal University of Santa Catarina, 88040-900 Florianópolis, Brazil

<sup>2</sup>STMicroelectronics, 38920 Crolles, France

<sup>3</sup>Univ. Grenoble Alpes, CNRS, Grenoble INP, TIMA F-38000, Grenoble, France

# Outline

- **Introduction**
- **Velocity saturation effects**
- **Parameter extraction**
- **Intrinsic capacitances including velocity saturation and DIBL**
- **Circuit examples**

# Introduction: democratizing IC design

Open source PDK



Open source EDA tools



Open source IP & libraries



Available compact MOSFET models



We propose: **simple** 5-DC-parameter  
MOSFET model



# Velocity saturation effects

Normalized current vs.  
normalized charge densities



$$i_D = \frac{(q_S + q_D + 2)}{1 + \zeta |q_S - q_D|} (q_S - q_D)$$

short-channel parameter :

diffusion-related velocity /saturation velocity

$$\zeta = \frac{(\mu_s \phi_t / L)}{v_{sat}}$$

**Saturation current due to saturation velocity of the carriers**

$$I_{Dsat} = -W Q_{Dsat} v_{sat}$$

$Q_{Dsat}$  is the saturation inversion charge density at the drain end of the channel

or using normalized variables

$$i_{Dsat} = \frac{2}{\zeta} q_{dsat}$$

# Physics-based saturation: design model

$$i_{Dsat} = \frac{2}{\zeta} q_{dsat} \qquad i_{Dsat} = \frac{(q_S + q_{Ds} + 2)}{1 + \zeta(q_S - q_{Ds})} (q_S - q_{Ds})$$

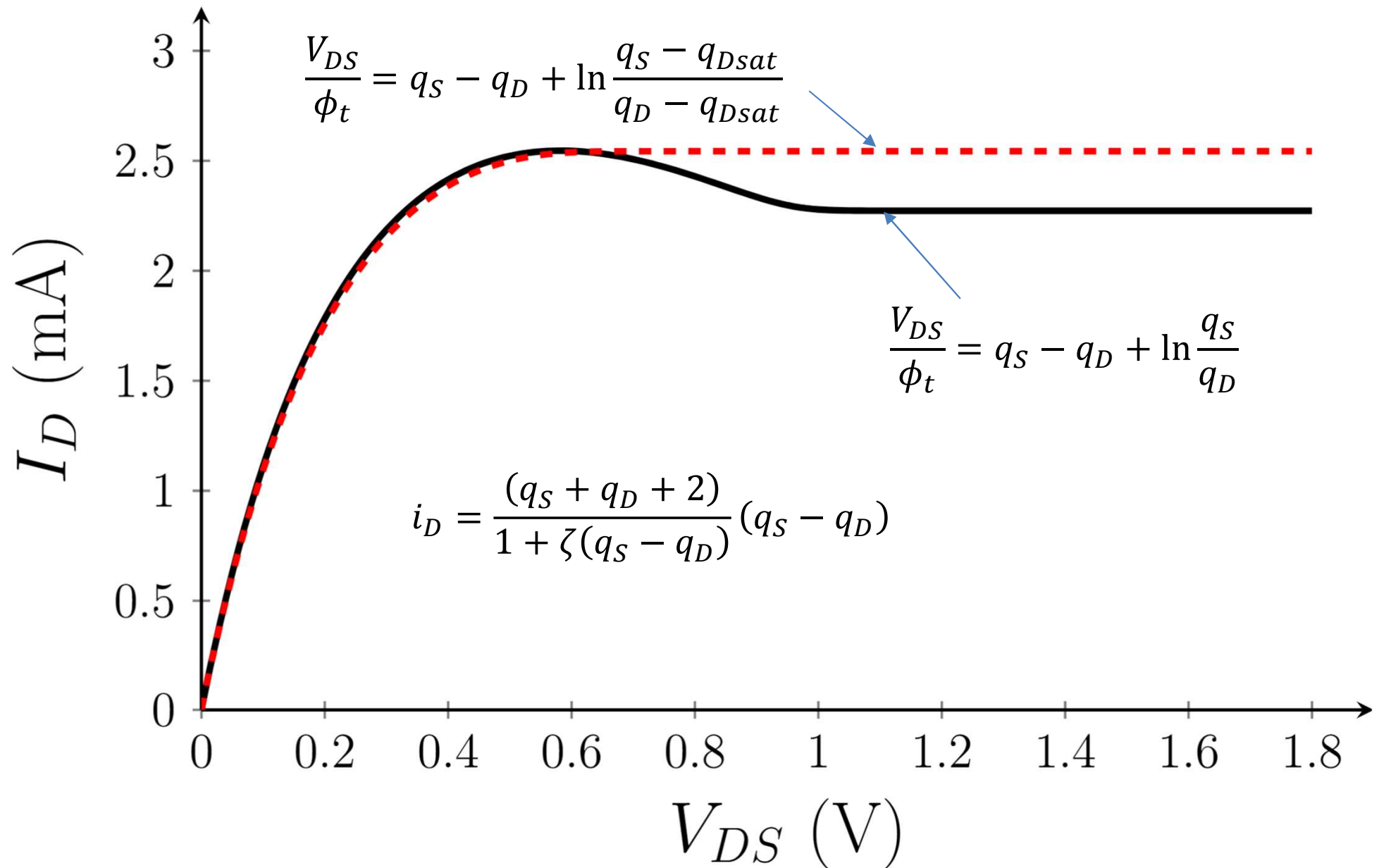
$$q_{Ds} = q_S + 1 + \frac{1}{\zeta} - \sqrt{\left(1 + \frac{1}{\zeta}\right)^2 + \frac{2q_S}{\zeta}}$$

***Unified Charge Control Model including the effect of velocity saturation***

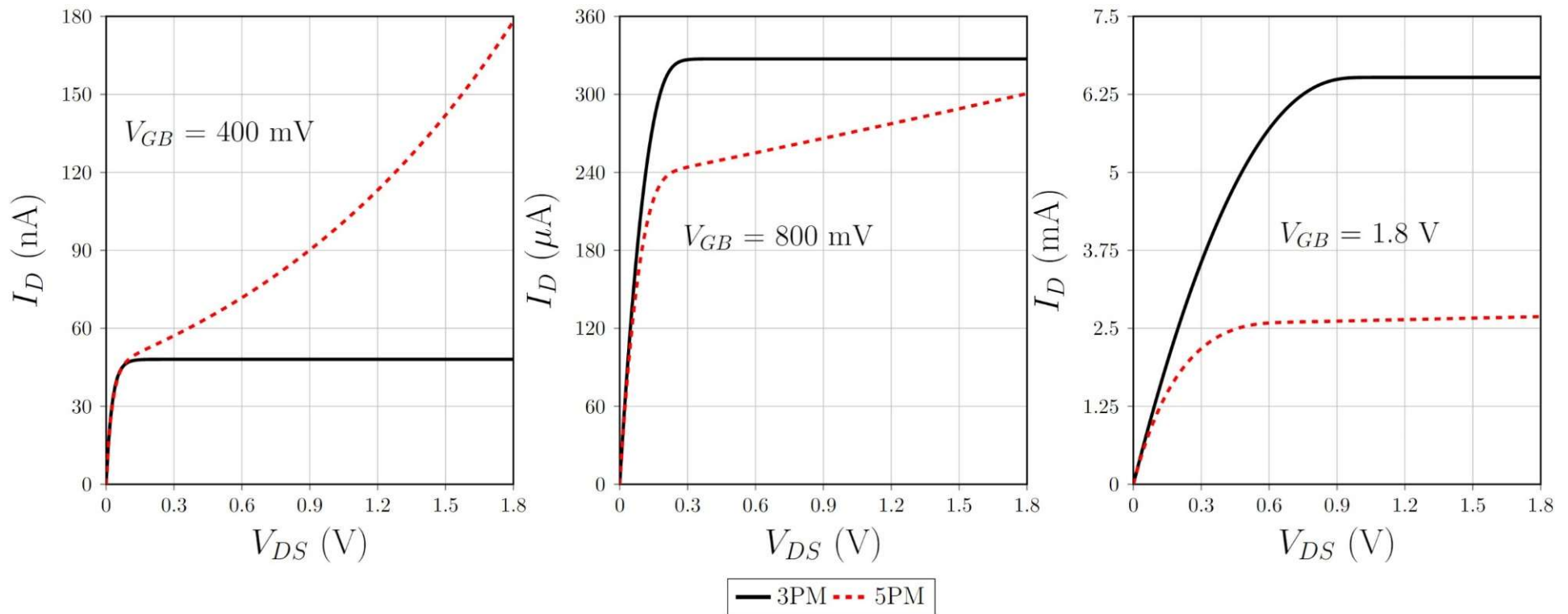
$$\frac{V_P - V_{S(D)B}}{\phi_t} = q_{S(D)} - q_{Ds} - 1 + \ln(q_{S(D)} - q_{Ds})$$

$$\phi_t = 26 \text{ mV@ } 300\text{K}$$

# Effect of the maximum of $i_D(q_D)$ on the output characteristic $i_D(v_D)$



# Output characteristics including DIBL and $v_{sat}$



*DIBL model:*  $V_T = V_{T0} - \sigma(V_{SB} + V_{DB})$

Transistor	$W/L$ ( $\mu m/\mu m$ )	$V_{T0}$ (mV)	$I_S$ ( $\mu A$ )	n	$\sigma$	$\zeta$
NMOS2V	5/0.18	528	5.52	1.37	0.025	0.056

# $V_T$ $I_S$ and $n$ extraction: The $g_m/I_D$ method

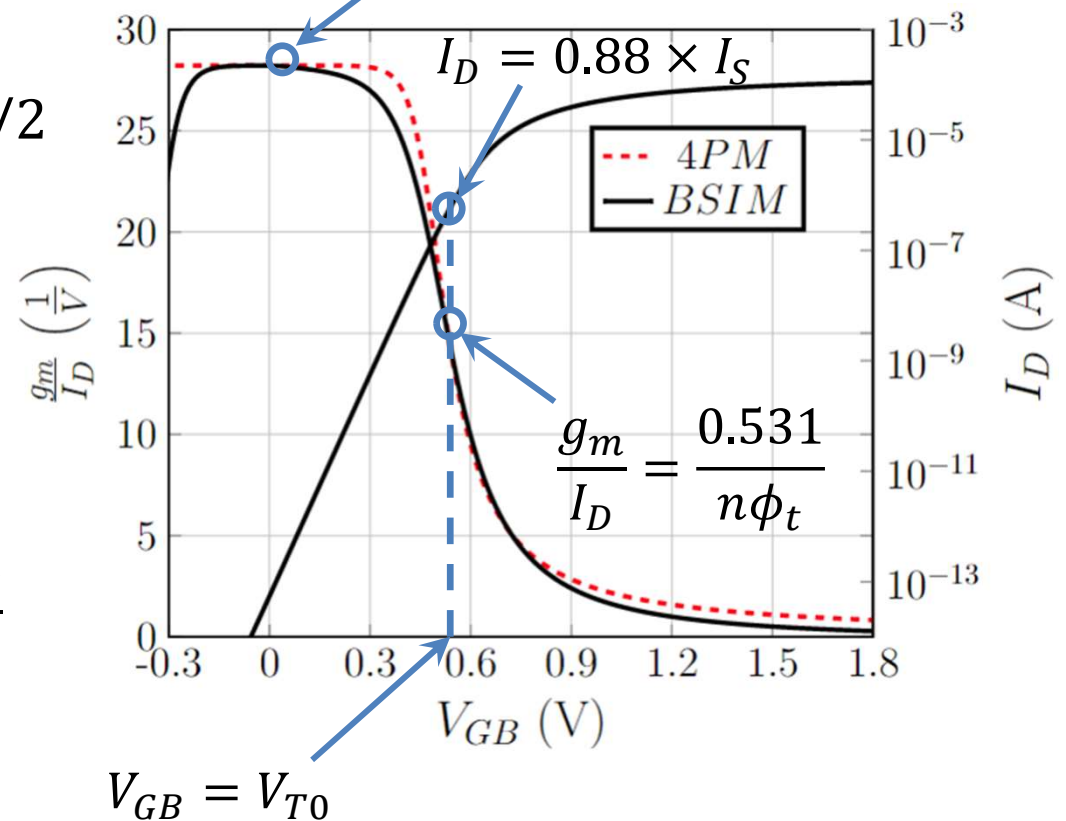
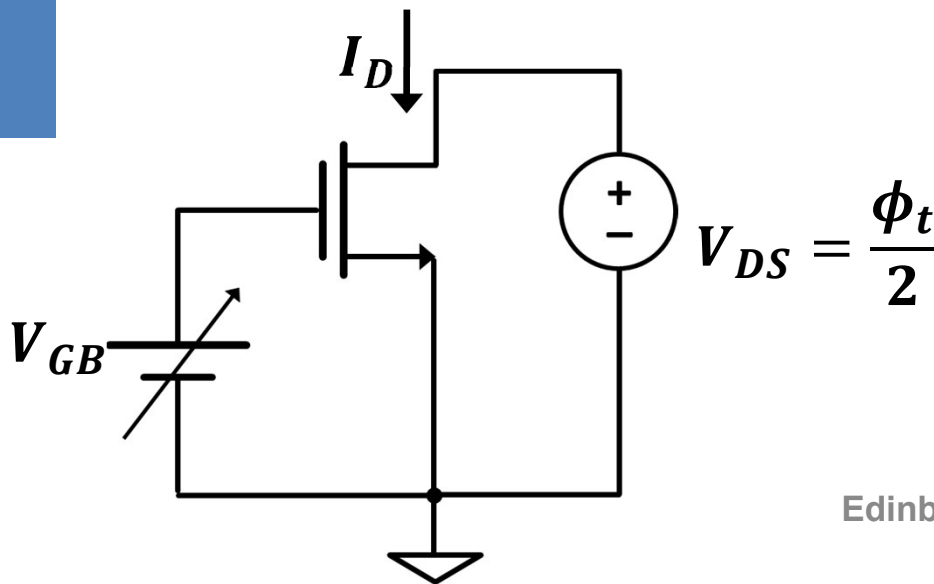
$$g_{ms} = \mu \frac{W}{L} n C_{ox} \phi_t q_S = \frac{2I_S}{\phi_t} q_S$$

$$\left. \frac{g_m}{I_D} \right|_{V_{DS} \rightarrow 0} = \frac{1}{n\phi_t(1 + q_S)}$$

Thus, at threshold ( $q_S = 1$ )  $g_m/I_D$  is at  
 **$\frac{1}{2}$  of its maximum value,**

$$\left( \frac{g_m}{I_D} \right)_{max} \cong \frac{1}{n\phi_t}$$

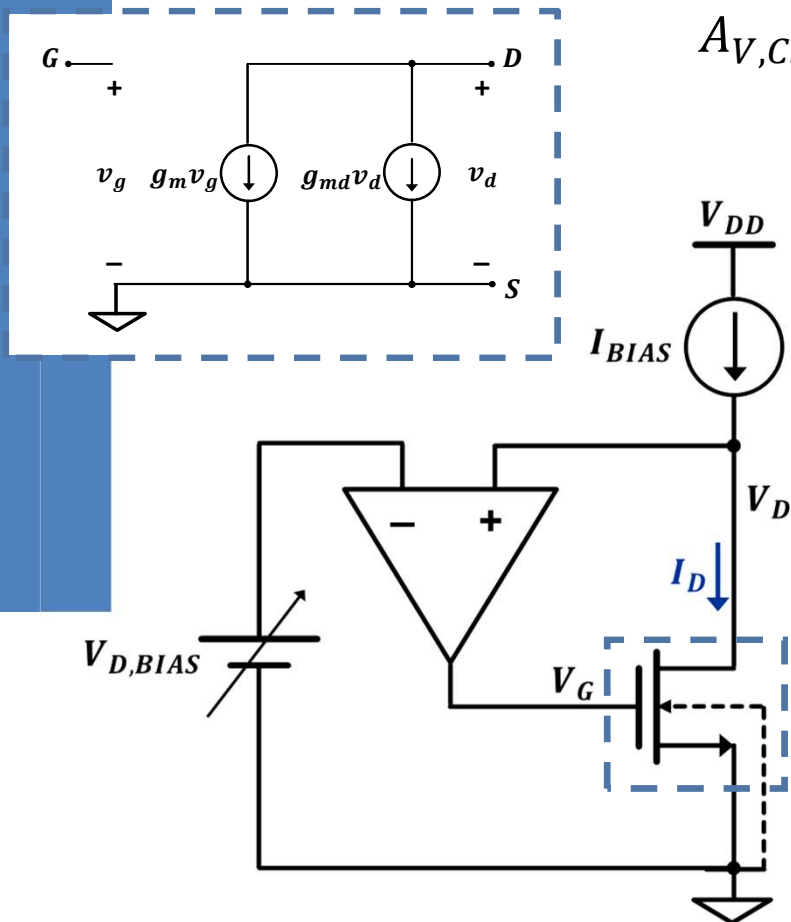
$$\begin{aligned} I_D(q_S = 1, V_{DS} = \phi_t/2) &\cong g_{ms}\phi_t/2 \\ &= \frac{2I_S}{\phi_t} \phi_t/2 = I_S \end{aligned}$$



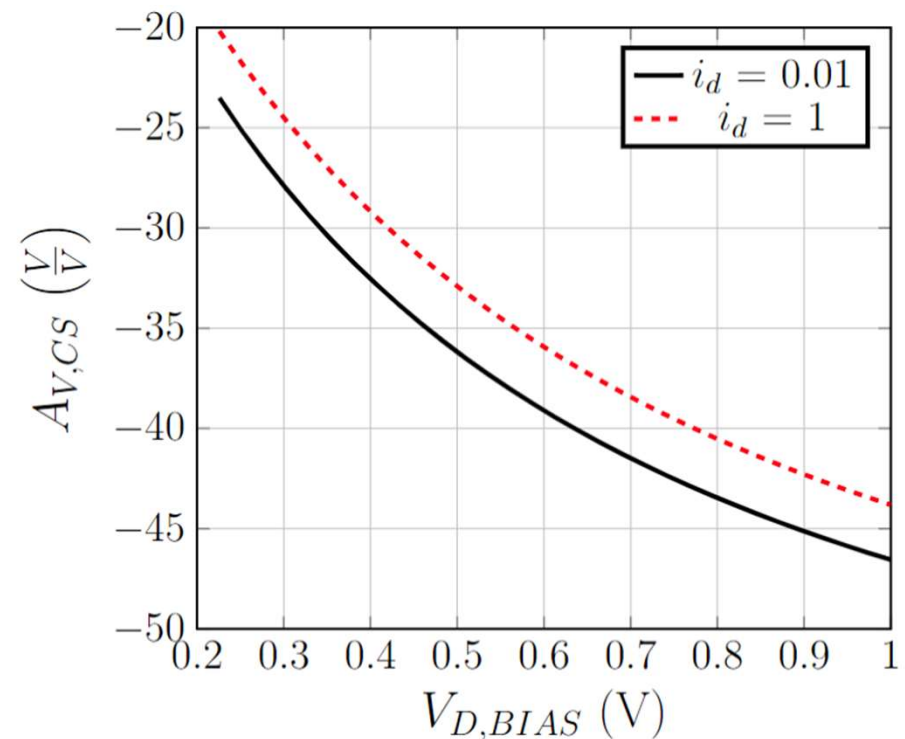


# Extraction of $\sigma$ in *WI (MI)* in saturation

## Common Source Intrinsic Gain method



$$A_{V,CS} = \frac{v_d}{v_g} = -\frac{g_m}{g_{md}} = -\frac{\frac{g_m}{I_{D,sat}}}{\frac{g_{md}}{I_{D,sat}}} = -\frac{\frac{1}{\phi_t} \left( \frac{1}{n} \right) \frac{2}{q_s + 2}}{\frac{1}{\phi_t} \left( \frac{\sigma}{n} \right) \frac{2}{q_s + 2}} = -\frac{1}{\sigma}$$

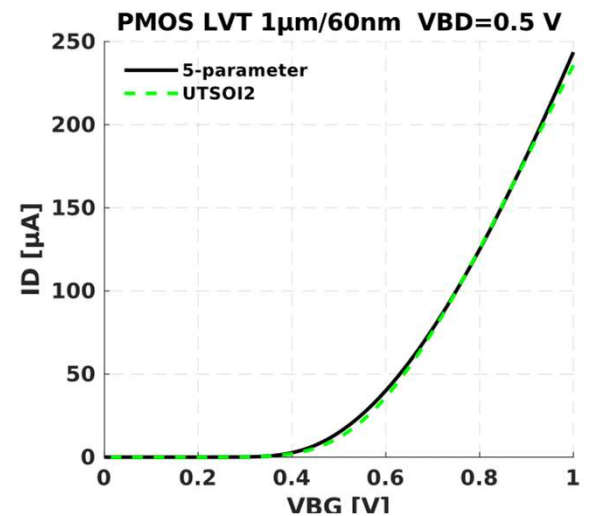
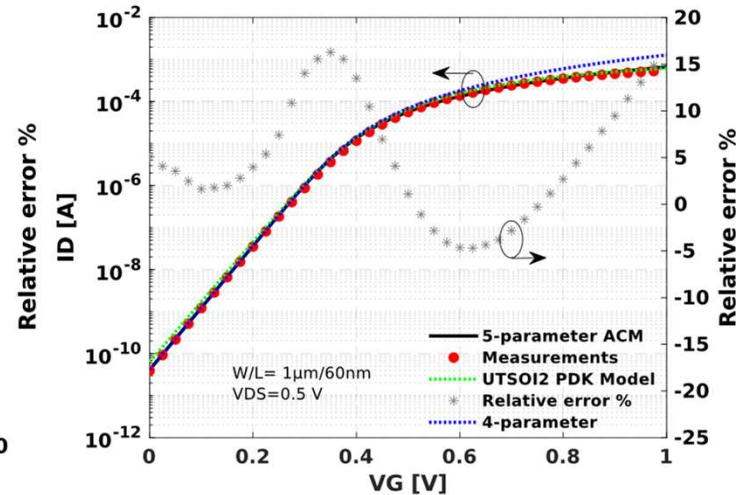
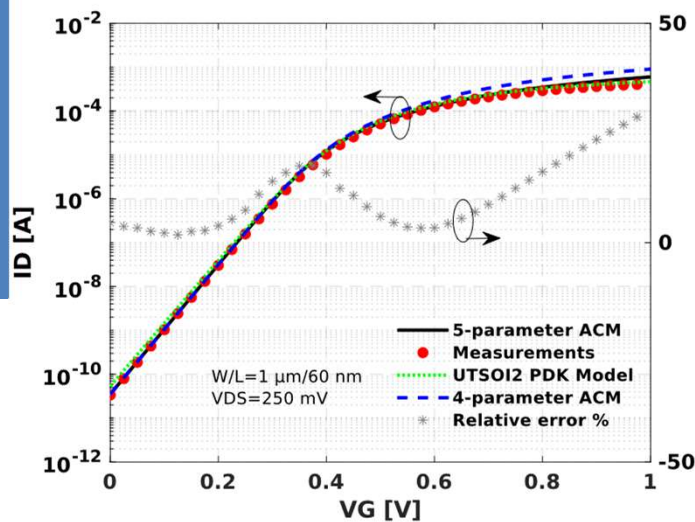


# 28 nm FD-SOI technology DC characteristics

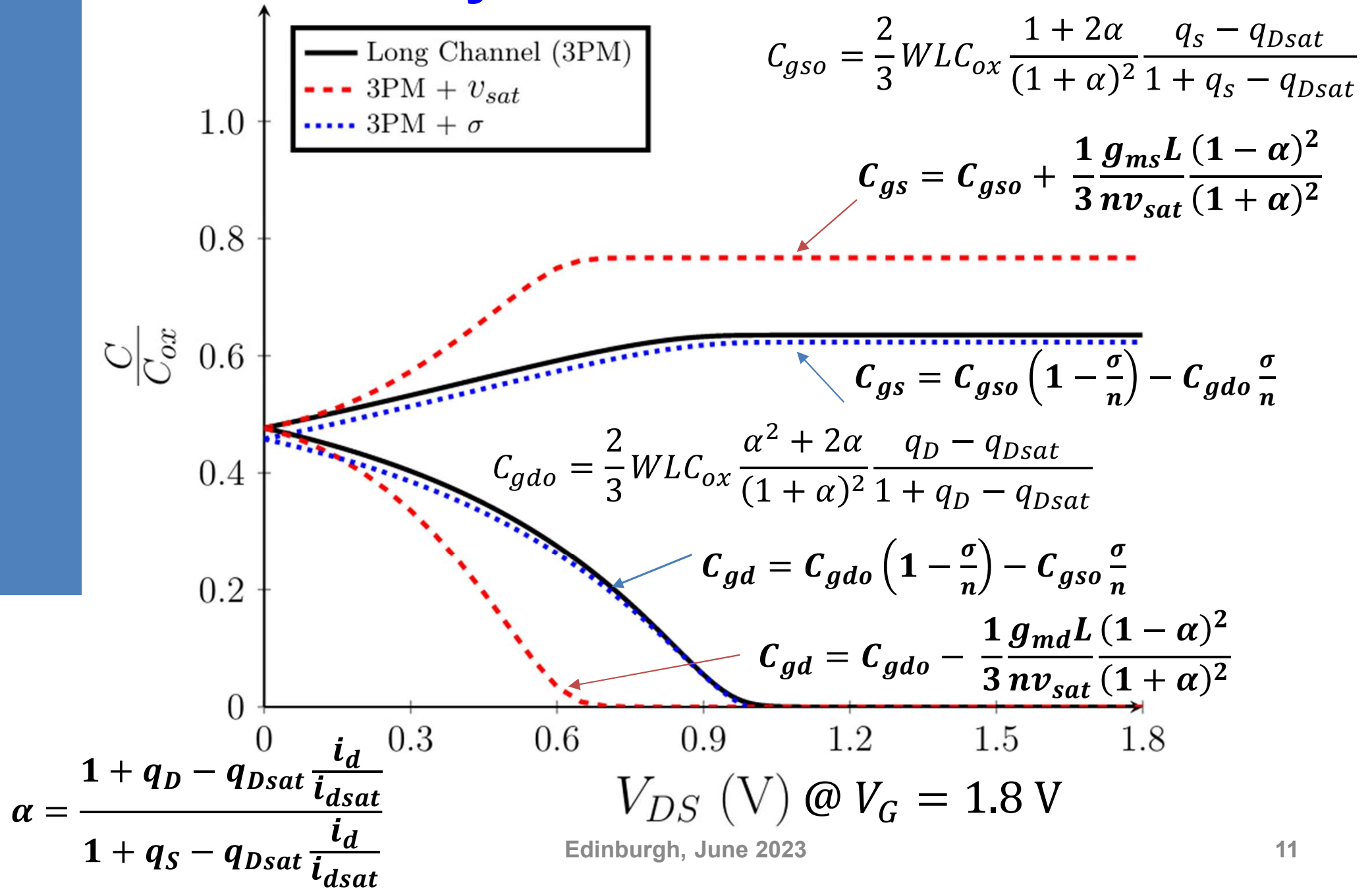
Parameter  
extraction  
for L=60 nm

Transistor	$W/L$	$V_{T0}$ (mV)	$I_S$ ( $\mu A$ )	$n$	$\sigma$	$\zeta$
LVTNMOS	1 $\mu m$ /60 nm	390.5	3.25	1.138	0.018	0.039
LVTNMOS	1 $\mu m$ /60 nm	390.5	3.25	1.138	0.018	0.039
LVTNPMOS	1 $\mu m$ /60 nm	403.6	0.755	1.014	0.029	0.024

## Model Verification: NMOS & PMOS TRANSISTORS

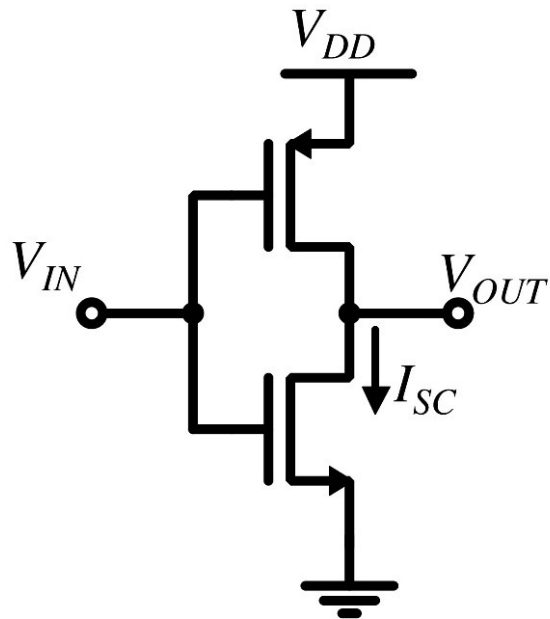


# Intrinsic capacitances including velocity saturation and DIBL



# CMOS Inverter

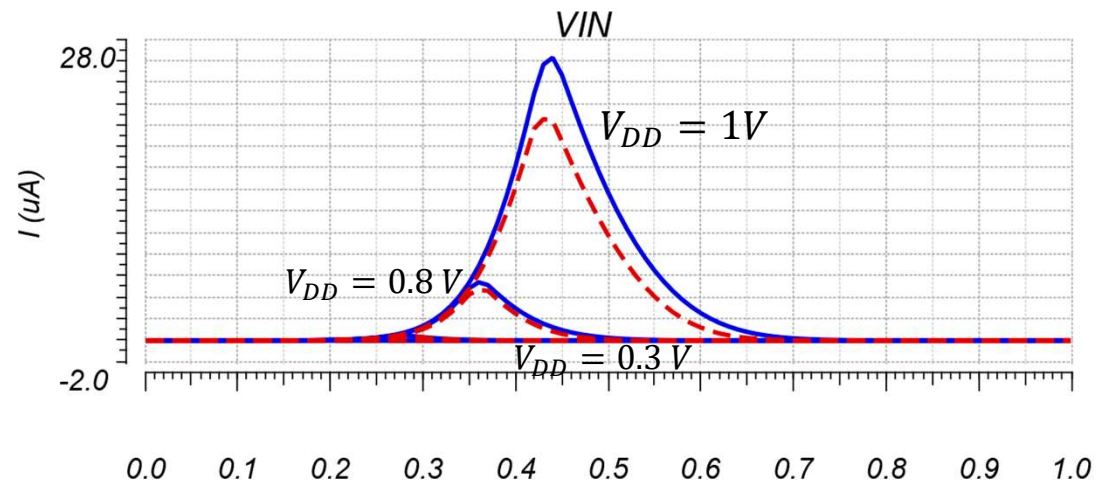
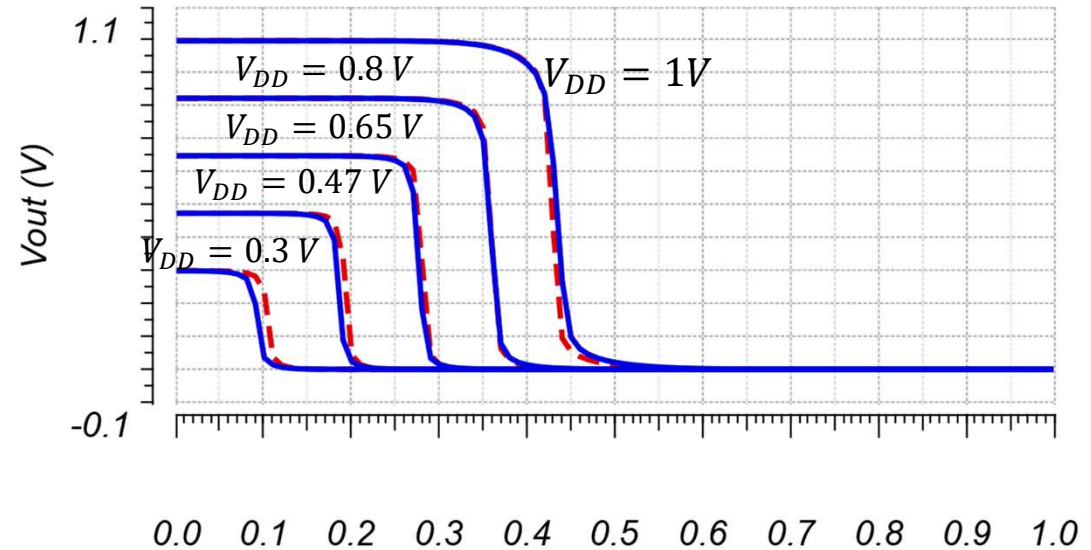
## VTC and short-circuit current in 28 nm FD-SOI



$$W_n = W_p = 1 \mu m$$

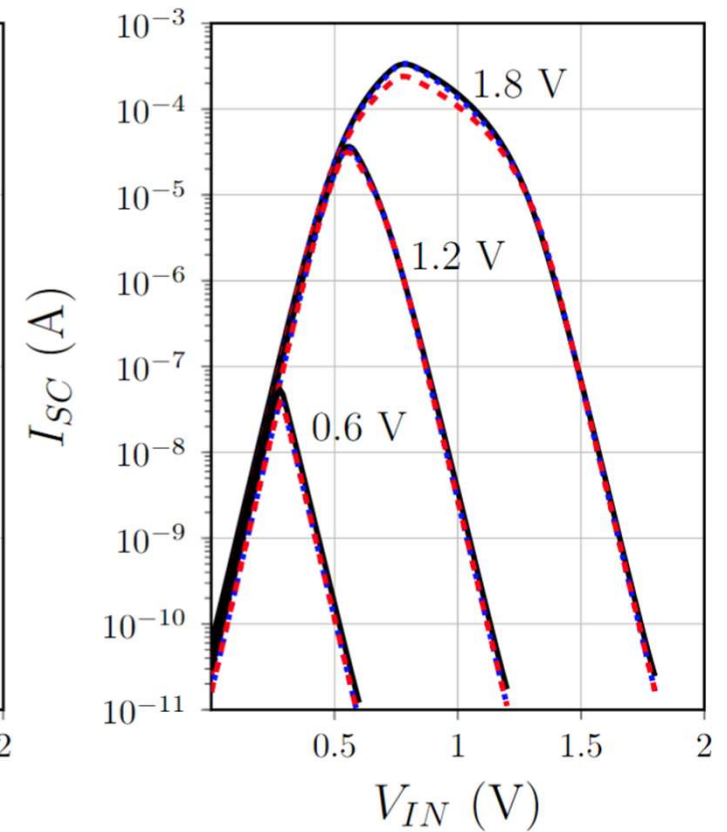
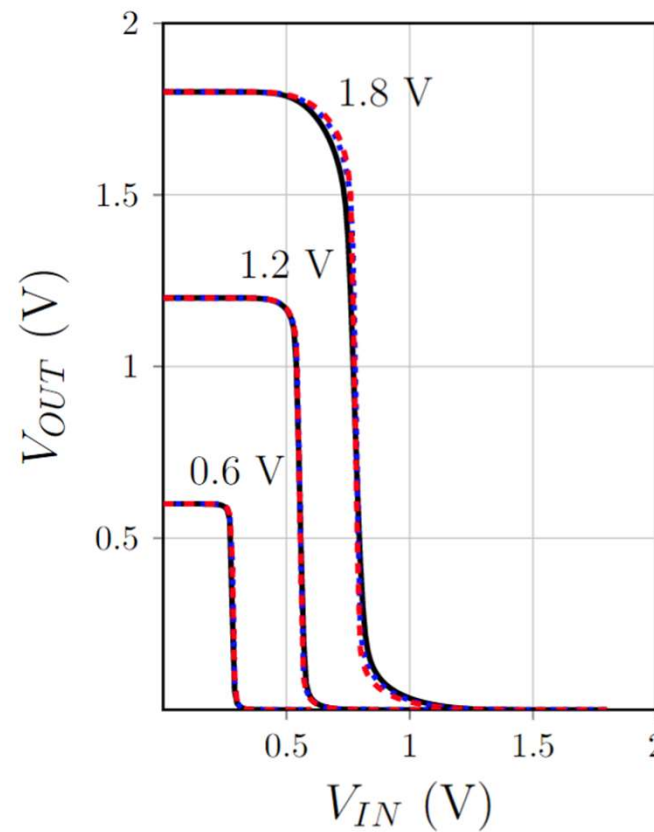
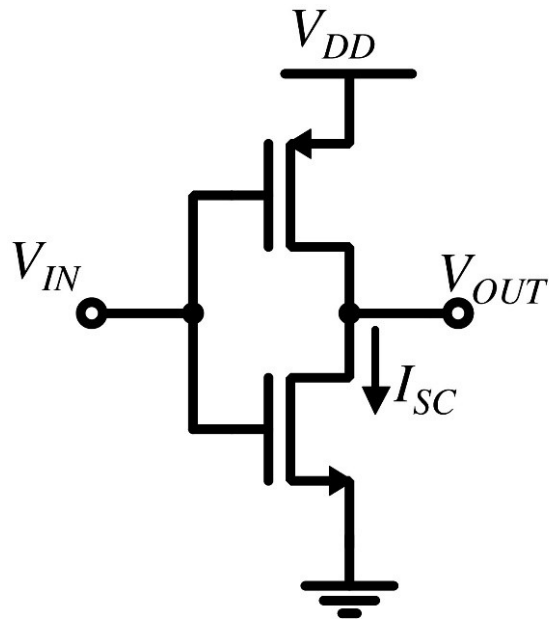
$$L_n = L_p = 60 nm$$

--- 5PM  
--- UTSOI2



# CMOS Inverter in 180 nm bulk

## VTC and short-circuit current

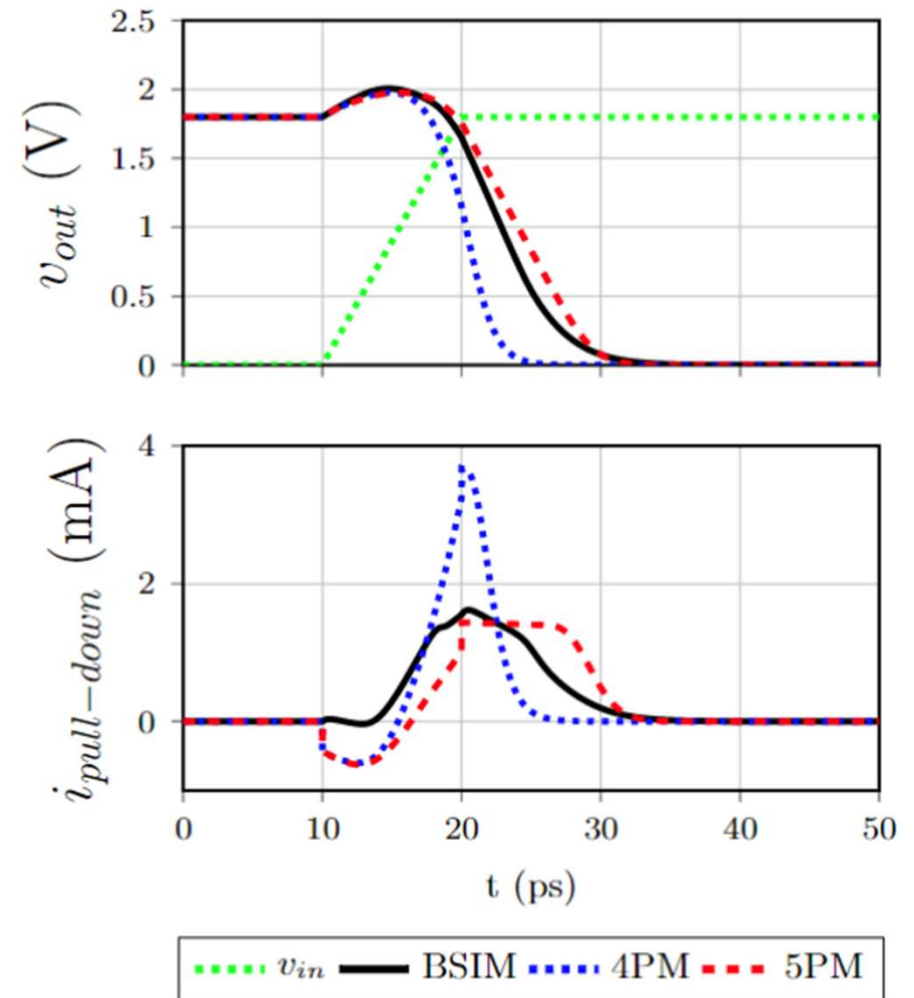
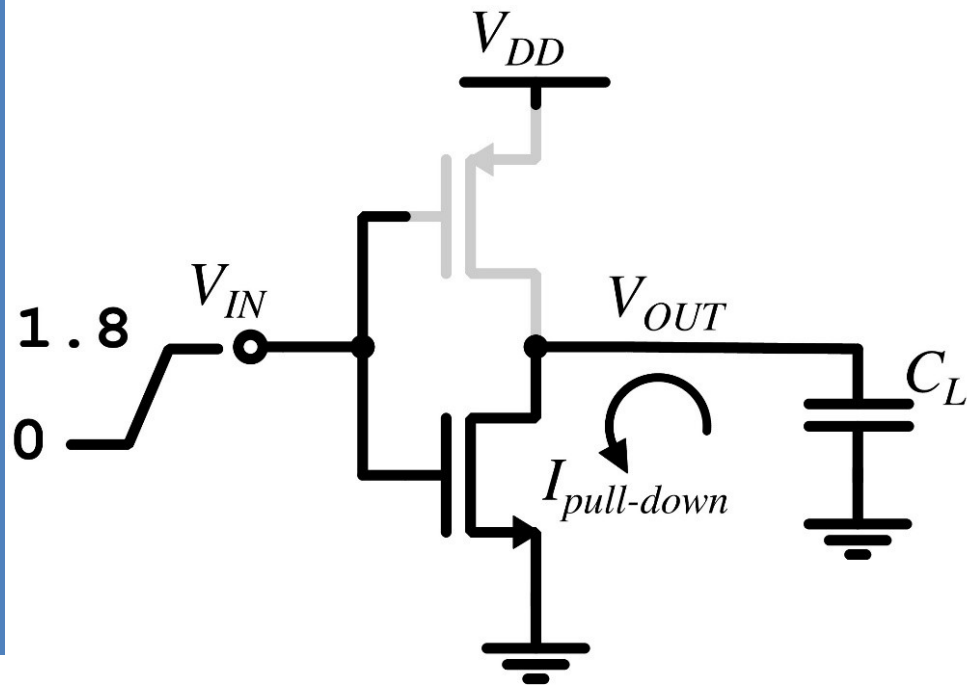


— BSIM    ..... 4PM    ---- 5PM

Transistor	$W/L$ ( $\mu m/\mu m$ )	$V_{T0}$ (mV)	$I_S$ ( $\mu A$ )	n	$\sigma$	$\zeta$
NMOS	5/0.18	528	5.52	1.37	0.027	0.056
PMOS	5/0.18	-525	1.82	1.40	0.024	0.035

# CMOS Inverter in 180 nm bulk

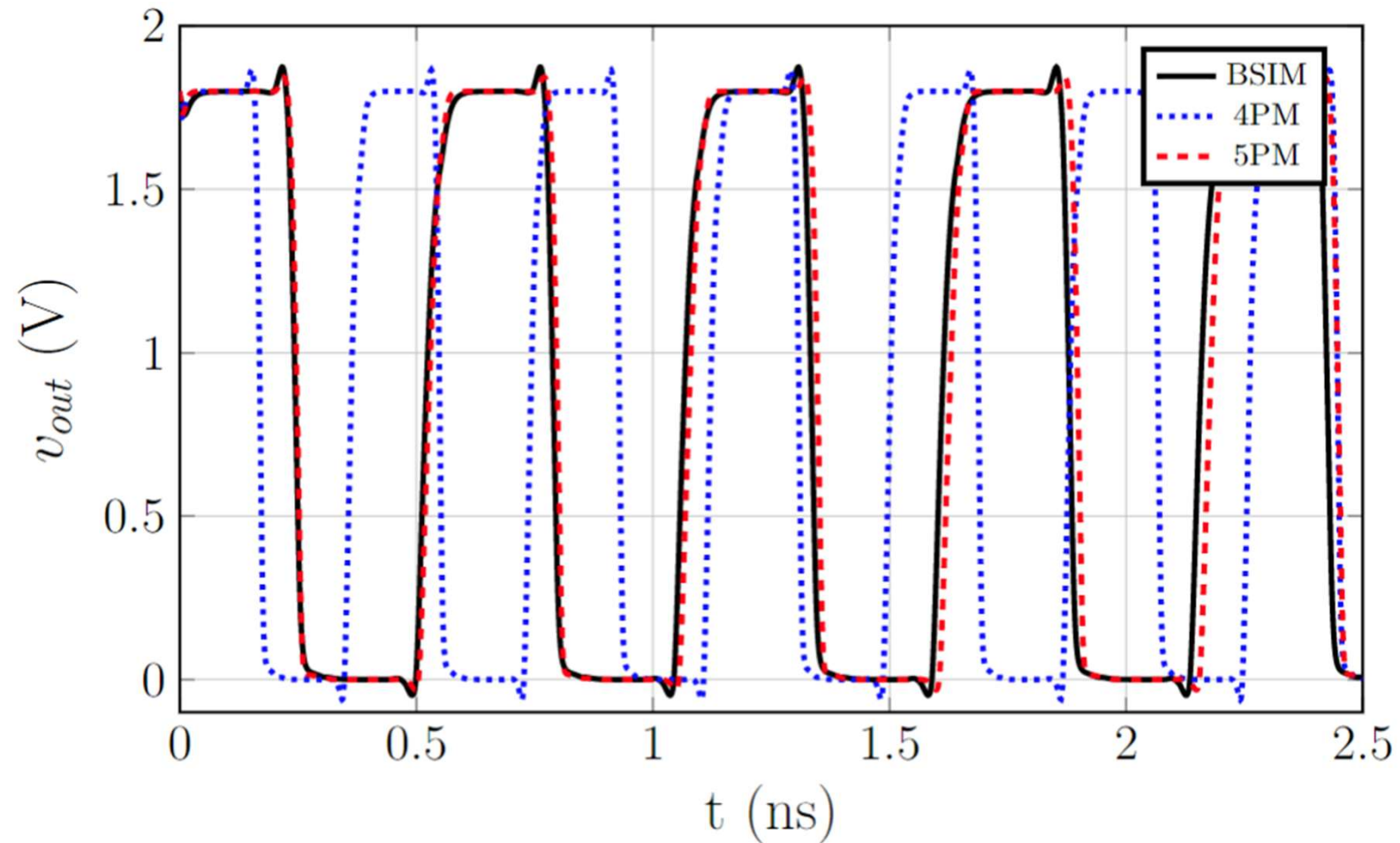
## Output Voltage and pull-down current





# 11- stage Ring Oscillator in 180 nm bulk

## Output Voltage



# Conclusion

- For the first time, a truly compact MOSFET model for SPICE formulated with single-piece functions
- With only 5 DC parameters that are extracted from simple and direct methods (automatized) using SPICE
- Good matching with circuit simulations with BSIM and UTSOI2 models



# Main References

- C. Galup-Montoro and M. C. Schneider, *MOSFET Modeling for circuit analysis and design*, World Scientific, 2007.
- C. M. Adornes, D. G. Alves Neto, M. C. Schneider and C. Galup-Montoro, "Bridging the gap between design and simulation of low-voltage CMOS circuits," *Journal of Low Power Electronics and Applications*, vol. 12, issue 2, June 2022.
- Accellera. Verilog-AMS reference manual. [Online]. Available: <https://www.accellera.org>



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